## DESCRIPTION

The 8275 is a QUAD LATCH circuit designed to provide temporary storage of four bits of information. A common application is as a holding register between a counter and a display driver (such as the 8280 and $8 \mathrm{TO1}$.) Separate enable lines to latches 1-2 and 3-4 allow individual control of each

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pair of latches. Initially, data is transferred on the rising edge of the enable pulse. While the enable is high, output Q follows the data input. When the enable falls, the input data present at fall time is retained at the Q output. Both Q and $\overline{\mathrm{Q}}$ are accessible.

## LOGIC DIAGRAM AND TRUTH TABLE



## ELECTRICAL CHARACTERISTICS (Over Recommended Operating Temperature And Voltage)

| CHARACTERISTICS | LIMITS |  |  |  | TEST CONDITIONS |  |  | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | MIN. | TYP. | MAX. | UNITS | DATA INPUT | ENABLE INPUT | OUTPUTS |  |
| " 1 " Output Voltage ( $\mathrm{Q}, \overline{\mathrm{O}}$ ) <br> " ${ }^{0}$ " Output Voltage ( $\mathrm{Q}, \overline{\mathrm{O}}$ ) | 2.6 | 3.5 | 0.4 | V |  |  | $\begin{array}{r} -800 \mu \mathrm{~A} \\ 16 \mathrm{~mA} \end{array}$ | $\begin{array}{ll} 6, & 11 \\ 7, & 11 \end{array}$ |
| "0'0 Input Current (Data) | -0.1 |  | -3.2 | mA | 0.4 V | 5.25 V |  |  |
| " 0 " Input Current (Enable) | -0.1 |  | -6.4 | mA | 5.25 V | 0.4 V |  |  |
| "1" Input Current (Data) |  |  | 80 | $\mu \mathrm{A}$ | 4.5 V | 0.0 V |  |  |
| "1" Input Current (Enable) |  |  | 160 | $\mu \mathrm{A}$ | 0.0V | 4.5 V |  |  |

$\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ and $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}$

| CHARACTERISTICS | LIMITS |  |  |  | TEST CONDITIONS |  |  | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | MIN. | TYP. | MAX. | UNITS | DATA INPUT | ENABLE INPUT | OUTPUTS |  |
| $\mathrm{t}_{\text {setup (1) at } \mathrm{D} \text { input }}$ |  | 12 | 20 | ns |  |  |  | 8, 12 |
| $\mathrm{t}_{\text {setup (0) at } \mathrm{D} \text { input }}$ |  | 14 | 20 | ns |  |  |  | 8, 12 |
| $t_{\text {hold (1) }}$ (1) D input | 0 | 15 |  | ns |  |  |  | 8,13 |
| ${ }^{\text {thold ( }} \mathbf{0}$ ) at D input | 0 | 6 |  | ns |  |  |  | 8,13 |
| ${ }^{\text {tpd ( }}$ (1) D to Q |  | 16 | 30 | ns |  |  |  | 8 |
| ${ }^{t} \mathrm{pd}(0) \mathrm{D}$ to Q |  | 14 | 25 | ns |  |  |  | 8 |
| ${ }^{\text {ppd (1) }} \mathrm{D}$ to $\overline{\mathrm{Q}}$ |  | 24 | 40 | ns |  |  |  | 8 |
| ${ }^{\text {tpd (0) }} \mathrm{D}$ to $\overline{\mathrm{Q}}$ |  | 7 | 15 | ns |  |  |  | 8 |
| $t_{\text {pd ( }}(1) \mathrm{E}$ to Q |  | 16 | 30 | ns |  |  |  | 8 |
| ${ }^{\text {tpd }}$ (0) E to Q |  | 12 | 20 | ns |  |  |  | 8 |
| ${ }^{\text {tpd (1) }}$ e to $\overline{\mathrm{Q}}$ |  | 16 | 30 | ns |  |  |  | 8 |
| $\mathrm{t}_{\text {pd }}(0) \mathrm{E}$ to $\overline{\mathrm{Q}}$ |  | 12 | 20 | ns |  |  |  | 8 |
| Power Consumption/Supply Current |  | 205/39 | 265/50 | $\mathrm{mW} / \mathrm{mA}$ |  |  |  | 14 |
| Input Voltage Rating (Data) | 5.5 |  |  | $v$ | 10 mA | 0.0V |  | 12 |
| Input Voltage Rating (Enable) | 5.5 |  |  | $v$ | 0.0V | 10 mA |  | 12 |
| Output Short Circuit Current | -20 |  | -70 | mA | 0.0V |  | 0.0V |  |

NOTES:

1. All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
2. All measurements are taken with ground pin tied to zero volts.
3. Positive current flow is defined as into the terminal referenced.
4. Positive NAND Logic Definition:
$"$ UP" Level $=" 1 "$ ", "DOWN" Level $=" 0 "$.
5. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
6. Output source current is supplied through a resistor to ground.
7. Output sink current is supplied through a resistor to $\mathrm{V}_{\mathrm{CC}}$ -
8. Refer to AC Test Figure.
9. Manufacturer reserves the right to make design and process changes and improvements.
10. Inputs for output voltage test is per TRUTH TABLE with threshold levels of 0.8 V for logical " $O$ " and 2.0 V for logical "1".
11. This test guarantees operation free of input latch-up over the specified operating power supply voltage range.
12. $t_{\text {setup }}$ is defined as the time prior to the fall of the clock.
13. thold is defined as the time after the fall of the clock.
14. $V_{C C}=5.25$ volts.

## SCHEMATIC DIAGRAM



## AC TEST FIGURES AND WAVEFORMS



## AC TEST FIGURES AND WAVEFORMS (Cont'd)



NOTES:

1. The pulse generators have the following characteristics: $V_{\text {gen }}=3 V, t_{1}=t_{0} \leqslant 10 n s$, and $Z_{\text {out }} \approx 50 \Omega$. For pulse generator $A$ tp $1=$ $1 \mu \mathrm{~s}$ and $\mathrm{PRR}=500 \mathrm{kHz}$. For pulse generator $\mathrm{B}, \mathrm{tp} 2=500 \mathrm{~ns}$ and $\mathrm{Prr}=1 \mathrm{MHz}$. Positions of D -input and enable input pulses are varied with respect to each other to verify setup and hold times.
2. Each latch is tested separately.
3. $\quad C_{L}$ includes probe and jig capacitance.
4. All diodes are 1 N916.
5. When measuring $t_{p d}{ }^{1}(D-Q), t_{p d} 0(D-Q), t_{p d} 0(D-\bar{Q})$, and $t_{p d} 1(D-\bar{Q})$, enable input must be held at logical 1 .

## TYPICAL APPLICATION

## OUTPUT STROBING OF RIPPLE COUNTER TO ACHIEVE SYNCHRONOUS OUTPUT CHANGES



